JAN 2 7 2006 W

SHEET 1 OF 2

Form PTO 1449		U.S. DEPARTMENT		ATTY DOCKET NO. TRADENAM	SERIAL NO. 10/810,831					
(Modified)		PATENT AND TRAD	EMARK OFFICE	250213US2CONT						
				APPLICANT						
LIST OF	REFE	RENCES CITED BY API	PLICANT	Katsuaki MIYAWAKI, et al.						
				FILING DATE		GROUP				
				March 29, 2004		2852				
U.S. PATENT DOCUMENTS										
EXAMINER INITIAL	DOCUMENT DAT		DATE	NAME	CLASS	SUB FILING DATE CLASS IF APPROPRIATE				
111175	AA	1			<del> </del>	05.00				
	AB	<del> </del>			-					
	AC									
	AD	<b> </b>								
	AE	1	-							
	AF	\			<del> </del>					
	AG				<del> </del>					
	АН	1								
	Al	1								
	AJ									
	AK	<b>†</b>								
	AL	<del>- 1</del>			1					
	AM									
	AN	\			<u> </u>					
	***	·	FO	REIGN PATENT DOCUMENTS						
•		DOCUMENT DATE COUNTRY TRANSLATION								
		NUMBER DATE COUNTRY				YES NO				
1, 6	AO	S61-167655	10/17/1986	JAPAN (w/ English translation)						
री 6	AP	6-195007	07/15/1994	JAPAN (w/ English Abstract)						
8/20	AQ	5-323781	12/07/1993	JAPAN (w/ English Abstract)						
1	AR .	1-166060	06/29/1989	JAPAN (w/ English Abstract)						
	AS	64-031173	01/02/1989	JAPAN (w/ English Abstract)			X			
	AT	2001-100488	04/13/2001	JAPAN (w/ English Abstract)						
	AU	5-100576	04/23/1993	JAPAN (w/ English Abstract)						
V	AV	2001-075449	03/23/2001	JAPAN (w/ English Abstract)						
$\chi \sim 1$	AW	11-38791	05/31/1989	JAPAN (w/ English Abstract)						
3		OTHER RE	FERENCES (I	ncluding Author, Title, Date, Pertinen	t Pages, et	c.)				
	4144			\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \						
	AW		,	\						
	AX						_			
	~			1						
	AY									
	,AZ				☐ Addi	ional Refe	ences sheet(s) attached			
	ÆП				Additional References sheet(s) attache					
Examiner		~ 4 ~			Date Considered 7-10-200					
*Examiner: Initial inveference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in										
conformance and not considered. Include copy of this form with next communication to applicant.										

		IAN 2 7 2006 M											
		_					<b>.</b>	E)	SHE	ET 2	OF	2	
Form PTO 1449	U.S. DEPARTMENT OF COMMERCE					ATTY DOCKET NO.			SERIAL NO.				
(Modified) PATENT AND TRADEMARK OFFICE				250213US2CONT			10/810,831						
						APPLICANT							
LIST OF REFERENCES CITED BY APPLICANT						Katsuaki MIYAWAKI, et al.							
						FILING DATE			GROUP				
						March 29, 2004			2852				
U.S. PATENT DOCUMENTS  EXAMINER DOCUMENT DATE NAME GLASS SUB FILING DATE													
EXAMINER INITIAL		DOCUMENT NUMBER			DATE	NAME		CLASS	SUB FILING				
	AA								_	_			
	AB	1	_										
	AC	1					<u> </u>						
	AD												
	AE												
	AF												
	AG		$I_{-}$										
	AH		$\bot$			·							
	Al		$\bot$							,			
	AJ		$\perp$				<del></del>						
	AK		$\longrightarrow$										
	AL			<b>_</b> _									
	AM			$ar{}$									
	AN			7			<del></del>		l				
					FO	REIGN PATENT DOCUM	ENTS						
		DOCUMENT DAT				COUNTRY			TRANSLATION YES NO				
XV6	AO	2000-221799			08/11/2000	JAPAN (w/ English Abst							
0	AP	5-212857			08/24/1993	JAPAN (w/ English Abst							
	AQ	10-039557			02/13/1998	JAPAN (w/ English Abst							
	AR	2001-75329			03/23/2001	JAPAN (w/ English Abst	<u> </u>						
	AS	11-109706			04/23/1999	JAPAN (w/ English Abst							
<del>                                     </del>	AT	7-261496			10/13/1995	JAPAN (w/ English Abst							
$\vdash \setminus h \dashv$	AU	2000-181142			06/30/2000 01/07/2000	JAPAN (w/ English Abst JAPAN (w/ English Abst							
2/2	AW	11-133696			05/21/1999	JAPAN (w/ English Abst		-	<del></del>				
X 61			OTHER			Including Author, Title, I	<del> :</del>	Pages, et	c.)	!			
	AW												
	AX												
	AY												
	742								Additional References sheet(s) attached				
Examiner								Date Considered 7-10-200 6					
*Examiner: Initial it reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.													
conformance and not considered. Include copy of this form with next communication to applicant.													